

# CEP02N6/CEB02N6

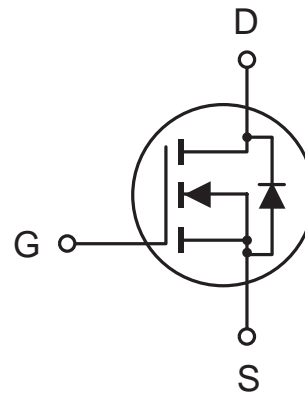
Sep. 2002

4

## N-Channel Logic Level Enhancement Mode Field Effect Transistor

### FEATURES

- 600V , 2A ,  $R_{DS(ON)}=5\Omega$  @  $V_{GS}=10V$ .
- Super high dense cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handling capability.
- TO-220 & TO-263 package.



### ABSOLUTE MAXIMUM RATINGS (Tc=25°C unless otherwise noted)

| Parameter  | Symbol                            | Limit      | Unit |
|--|-----------------------------------|------------|------|
| Drain-Source Voltage   | V <sub>DS</sub>                   | 600        | V    |
| Gate-Source Voltage  | V <sub>GS</sub>                   | ± 30       | V    |
| Drain Current-Continuous<br>-Pulsed                                  | I <sub>D</sub>                    | 2          | A    |
|  | I <sub>DM</sub>                   | 6          | A    |
| Drain-Source Diode Forward Current                                   | I <sub>S</sub>                    | 6          | A    |
| Maximum Power Dissipation @T <sub>c</sub> =25°C<br>Derate above 25°C | P <sub>D</sub>                    | 60         | W    |
|  |                                   | 0.48       | W/°C |
| Operating and Storage Temperature Range                              | T <sub>J</sub> , T <sub>STG</sub> | -55 to 150 | °C   |

### THERMAL CHARACTERISTICS

|   |                  |      |      |
|---|------------------|------|------|
| Thermal Resistance, Junction-to-Case    | R <sub>θJC</sub> | 2.1  | °C/W |
| Thermal Resistance, Junction-to-Ambient | R <sub>θJA</sub> | 62.5 | °C/W |

4-2

# CEP02N6/CEB02N6

## ELECTRICAL CHARACTERISTICS (Tc=25°C unless otherwise noted)

4

| Parameter  | Symbol              | Condition  | Min | Typ | Max  | Unit |
|--|---------------------|--|-----|-----|------|------|
| <b>DRAIN-SOURCE AVALANCHE RATING<sup>a</sup></b> |                     |  |     |     |      |      |
| Single Pulse Avalanche Energy <sup>c</sup>       | EAS                 |  |     | 125 |      | mJ   |
| Avalanche Current                                | IAR                 |  |     | 2   |      | A    |
| Repetitive Avalanche Energy                      | EAR                 |  |     | 5.4 |      | mJ   |
| <b>OFF CHARACTERISTICS</b>                       |                     |  |     |     |      |      |
| Drain-Source Breakdown Voltage                   | BV <sub>DSS</sub>   | V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA   | 600 |     |      | V    |
| Zero Gate Voltage Drain Current                  | I <sub>DSS</sub>    | V <sub>DS</sub> = 600V, V <sub>GS</sub> = 0V   |     |     | 25   | μA   |
| Gate-Body Leakage                                | I <sub>GSS</sub>    | V <sub>GS</sub> = ±30V, V <sub>DS</sub> = 0V   |     |     | ±100 | nA   |
| <b>ON CHARACTERISTICS<sup>a</sup></b>            |                     |  |     |     |      |      |
| Gate Threshold Voltage                           | V <sub>GS(th)</sub> | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA   | 2   |     | 4    | V    |
| Drain-Source On-State Resistance                 | R <sub>DS(ON)</sub> | V <sub>GS</sub> = 10V, I <sub>D</sub> = 1A   |     | 3.8 | 5.0  | Ω    |
| On-State Drain Current                           | I <sub>D(ON)</sub>  | V <sub>GS</sub> = 10V, V <sub>DS</sub> = 10V   | 2   |     |      | A    |
| Forward Transconductance                         | g <sub>FS</sub>     | V <sub>DS</sub> = 50V, I <sub>D</sub> = 1A   |     | 1.2 |      | S    |
| <b>SWITCHING CHARACTERISTICS<sup>b</sup></b>     |                     |  |     |     |      |      |
| Turn-On Delay Time                               | t <sub>D(ON)</sub>  | V <sub>DD</sub> = 300V,<br>I <sub>D</sub> = 2A,<br>V <sub>GS</sub> = 10V<br>R <sub>GEN</sub> = 18Ω |     | 18  | 35   | ns   |
| Rise Time  | t <sub>r</sub>      |  |     | 18  | 35   | ns   |
| Turn-Off Delay Time                              | t <sub>D(OFF)</sub> |  |     | 50  | 90   | ns   |
| Fall Time  | t <sub>f</sub>      |  |     | 16  | 40   | ns   |
| Total Gate Charge                                | Q <sub>g</sub>      | V <sub>DS</sub> = 480V, I <sub>D</sub> = 2A,<br>V <sub>GS</sub> = 10V                              |     | 20  | 25   | nC   |
| Gate-Source Charge                               | Q <sub>gs</sub>     |  |     | 2   |      | nC   |
| Gate-Drain Charge                                | Q <sub>gd</sub>     |  |     | 12  |      | nC   |

4-3

# CEP02N6/CEB02N6

4

## ELECTRICAL CHARACTERISTICS ( $T_c=25^\circ\text{C}$ unless otherwise noted)

| Parameter   | Symbol    | Condition  | Min | Typ | Max | Unit |
|---|-----------|--|-----|-----|-----|------|
| <b>DYNAMIC CHARACTERISTICS<sup>b</sup></b>            |           |  |     |     |     |      |
| Input Capacitance                                     | $C_{iss}$ | $V_{DS}=25\text{V}, V_{GS}=0\text{V}$<br>$f=1.0\text{MHz}$ |     | 250 |     | pF   |
| Output Capacitance                                    | $C_{oss}$ |  |     | 50  |     | pF   |
| Reverse Transfer Capacitance                          | $C_{rss}$ |  |     | 30  |     | pF   |
| <b>DRAIN-SOURCE DIODE CHARACTERISTICS<sup>a</sup></b> |           |  |     |     |     |      |
| Diode Forward Voltage                                 | $V_{SD}$  | $V_{GS}=0\text{V}, I_S=2\text{A}$                          |     |     | 1.5 | V    |

### Notes

- a. Pulse Test: Pulse Width  $\leq 300 \mu\text{s}$ , Duty Cycle  $\leq 2\%$ .
- b. Guaranteed by design, not subject to production testing.
- c.  $L=60\text{mH}$ ,  $I_{AS}=2.0\text{A}$ ,  $V_{DD}=50\text{V}$ ,  $R_G=25\Omega$ , Starting  $T_J=25^\circ\text{C}$

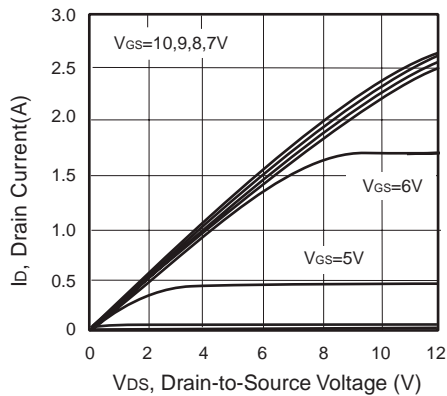


Figure 1. Output Characteristics

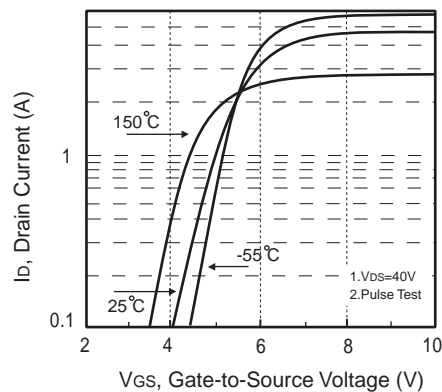
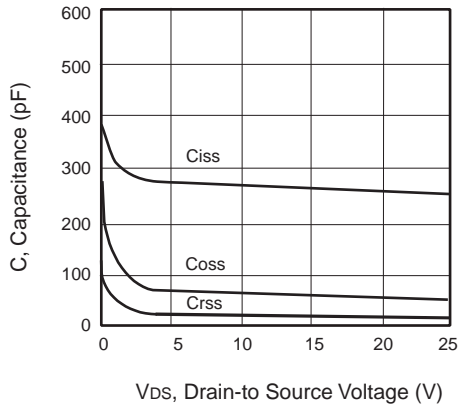
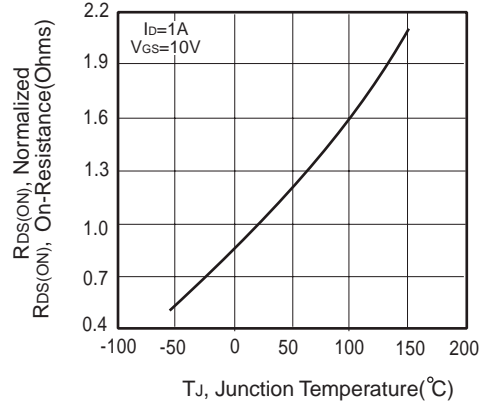


Figure 2. Transfer Characteristics

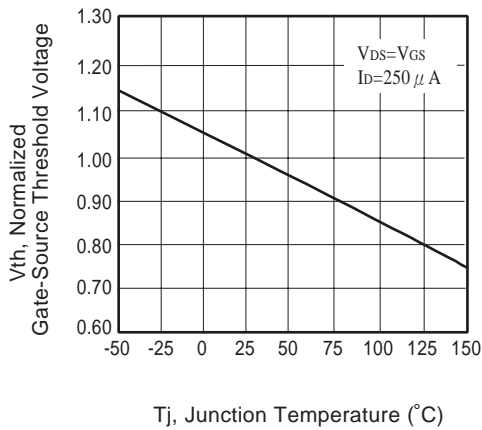
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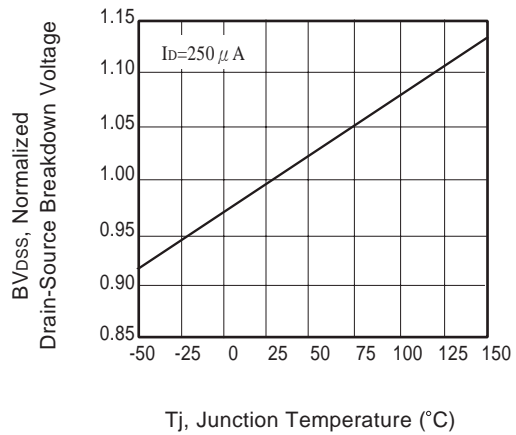
**Figure 3. Capacitance**



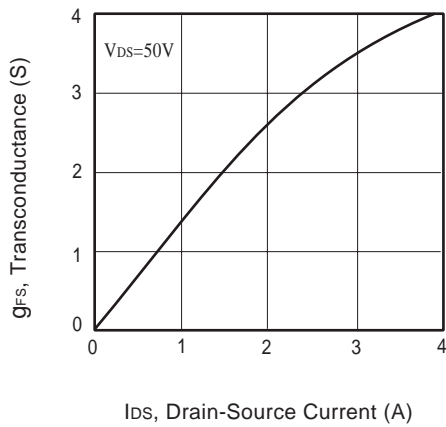
**Figure 4. On-Resistance Variation with Temperature**



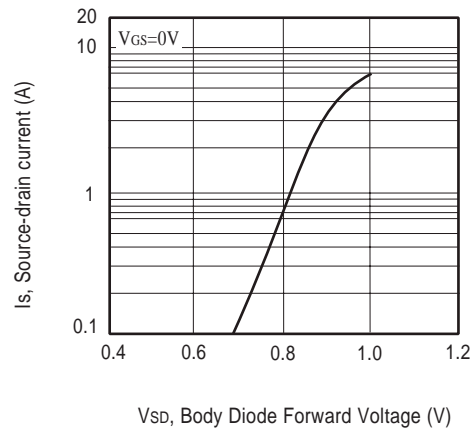
**Figure 5. Gate Threshold Variation with Temperature**



**Figure 6. Breakdown Voltage Variation with Temperature**



**Figure 7. Transconductance Variation with Drain Current**



**Figure 8. Body Diode Forward Voltage Variation with Source Current**

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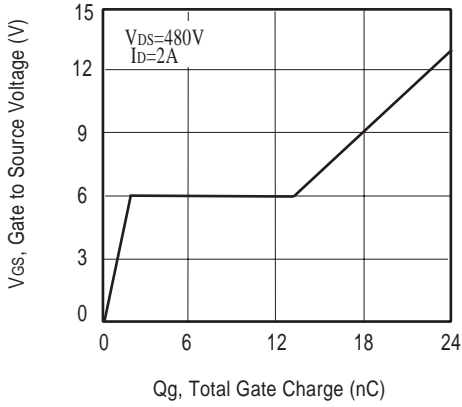


Figure 9. Gate Charge

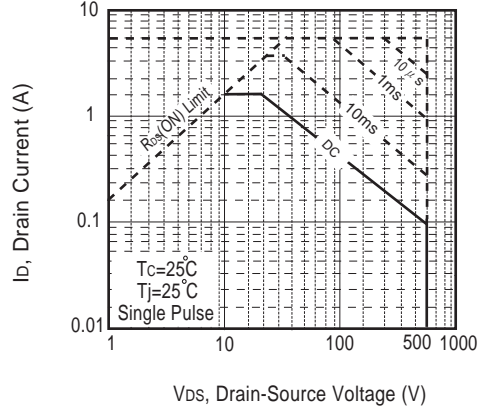


Figure 10. Maximum Safe Operating Area

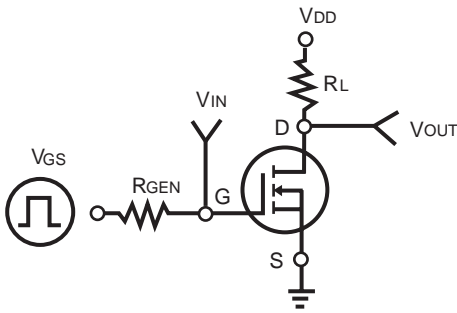


Figure 11. Switching Test Circuit

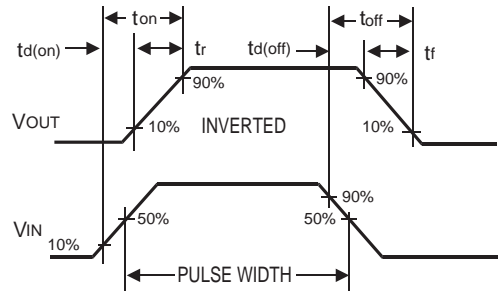


Figure 12. Switching Waveforms

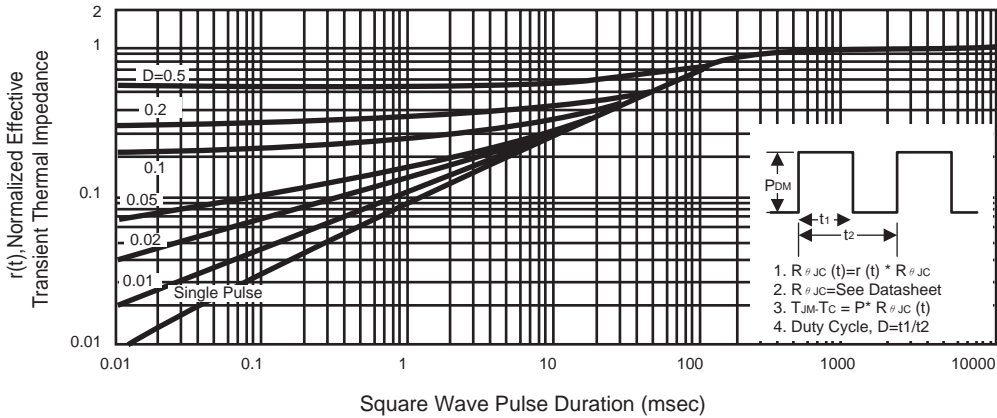


Figure 13. Normalized Thermal Transient Impedance Curve